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# DATA SHEET

## **74F125, 74F126** Quad buffers (3-State)

Product specification  
IC15 Data Handbook

1989 March 28

# Quad buffers (3-State)

# 74F125, 74F126

## FEATURE

- High impedance NPN base inputs for reduced loading (20µA in High and Low states)

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F125	5.0ns	23mA
74F126	5.0ns	26mA

## ORDERING INFORMATION

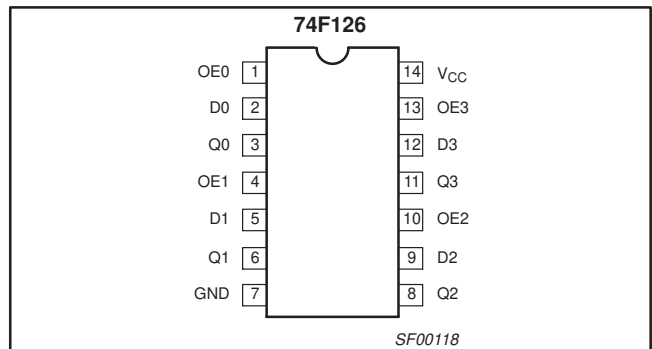
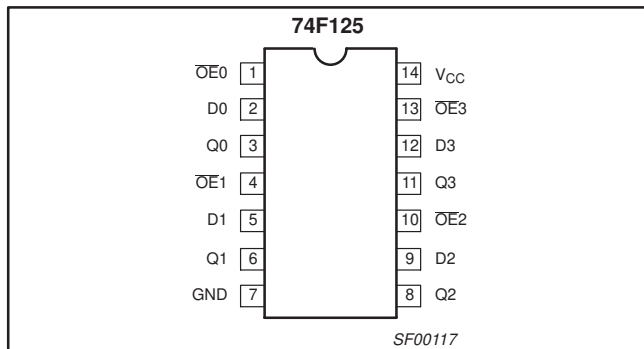
DESCRIPTION	COMMERCIAL RANGE V <sub>CC</sub> = 5V ±10%, T <sub>amb</sub> = 0°C to +70°C	PKG DWG #
14-pin plastic DIP	N74F125N, N74F126N	SOT27-1
14-pin plastic SO	N74F125D, N74F126D	SOT108-1

## INPUT AND OUTPUT LOADING AND FAN OUT TABLE

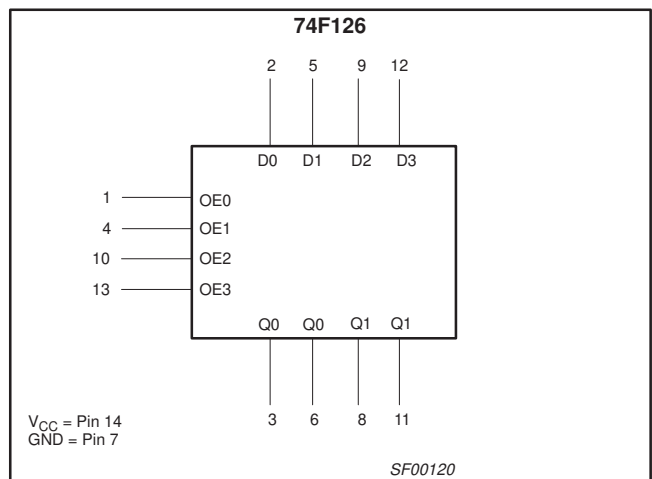
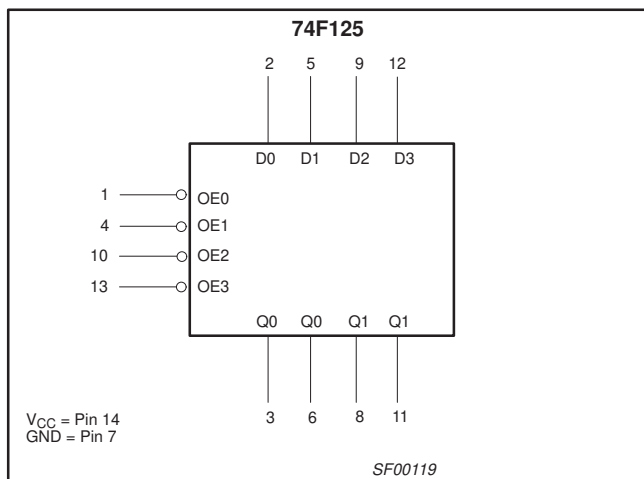
PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
D0–D3	Data inputs	1.0/0.033	20µA/20µA
$\overline{OE}0$ – $\overline{OE}3$	Output Enable inputs (active Low), 74F125	1.0/0.033	20µA/20µA
OE0–OE3	Output Enable inputs (active High), 74F126	1.0/0.033	20µA/20µA
Q0–Q3	Data outputs	750/106.7	15mA/64mA

NOTE: One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

## PIN CONFIGURATIONS



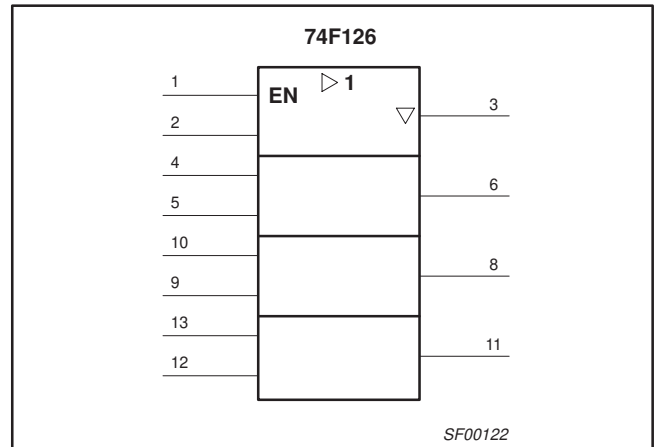
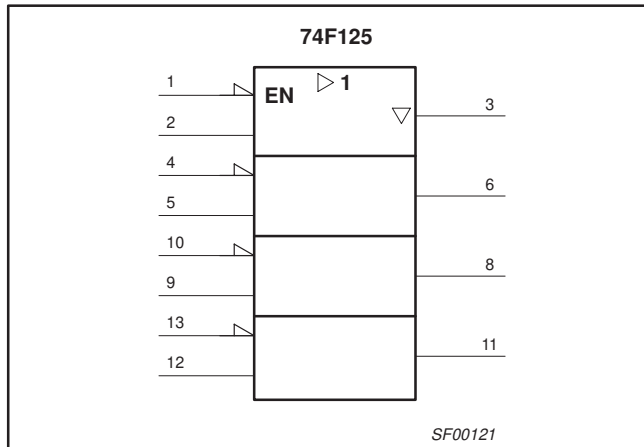
## LOGIC SYMBOLS



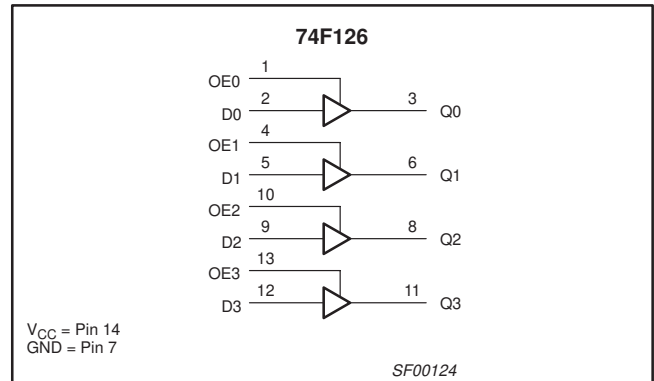
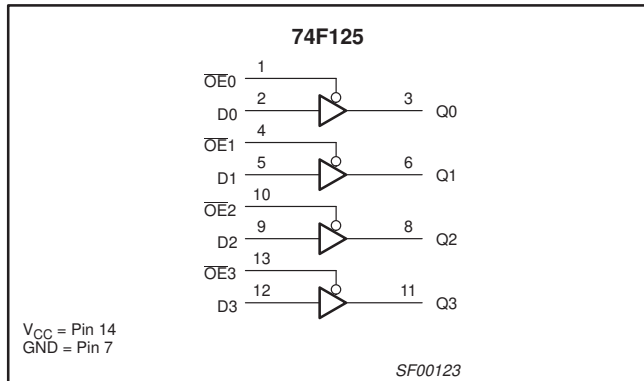
# Quad buffers (3-State)

# 74F125, 74F126

## IEC/IEEE SYMBOLS



## LOGIC DIAGRAMS



## FUNCTION TABLE, 74F125

I INPUTS		OUTPUT
$\overline{OEn}$	$D_n$	$Q_n$
L	L	L
L	H	H
H	X	Z

## FUNCTION TABLE, 74F126

I INPUTS		OUTPUT
$OEn$	$D_n$	$Q_n$
H	L	L
H	H	H
L	X	Z

### NOTES TO THE FUNCTION TABLES:

- H = High voltage level
- L = Low voltage level
- X = Don't care
- Z = High impedance "off" state

## ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
$V_{CC}$	Supply voltage	-0.5 to +7.0	V
$V_{IN}$	Input voltage	-0.5 to +7.0	V
$I_{IN}$	Input current	-30 to +5	mA
$V_{OUT}$	Voltage applied to output in High output state	-0.5 to $V_{CC}$	V
$I_{OUT}$	Current applied to output in Low output state	128	mA
$T_{amb}$	Operating free-air temperature range	0 to +70	°C
$T_{stg}$	Storage temperature range	-65 to +150	°C

## Quad buffers (3-State)

74F125, 74F126

## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		MIN	NOM	MAX	
V <sub>CC</sub>	Supply voltage	4.5	5.0	5.5	V
V <sub>IH</sub>	High-level input voltage	2.0			V
V <sub>IL</sub>	Low-level input voltage			0.8	V
I <sub>IK</sub>	Input clamp current			-18	mA
I <sub>OH</sub>	High-level output current			-15	mA
I <sub>OL</sub>	Low-level output current			64	mA
T <sub>amb</sub>	Operating free air temperature range	0		+70	°C

## DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT			
			MIN	TYP <sup>2</sup>	MAX				
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX, V <sub>IH</sub> = MIN	I <sub>OH</sub> = -3mA	±10%V <sub>CC</sub>	2.4		V		
				±5%V <sub>CC</sub>	2.7	3.3	V		
			I <sub>OH</sub> = -15mA	±10%V <sub>CC</sub>	2.0		V		
				±5%V <sub>CC</sub>	2.0		V		
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IL</sub> = MAX, V <sub>IH</sub> = MIN	I <sub>OH</sub> = MAX	±10%V <sub>CC</sub>		0.55	V		
				±5%V <sub>CC</sub>		0.42	0.55	V	
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = I <sub>IK</sub>			-0.73	-1.2	V		
I <sub>I</sub>	Input current at maximum input voltage	V <sub>CC</sub> = 0.0V, V <sub>I</sub> = 7.0V				100	μA		
I <sub>IH</sub>	High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7V				20	μA		
I <sub>IL</sub>	Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5V				-20	μA		
I <sub>OZH</sub>	Off-state output current, High-level voltage applied	V <sub>CC</sub> = MAX, V <sub>O</sub> = 2.7V				50	μA		
I <sub>OZL</sub>	Off-state output current, Low-level voltage applied	V <sub>CC</sub> = MAX, V <sub>O</sub> = 0.5V				-50	μA		
I <sub>OS</sub>	Short circuit output current <sup>3</sup>	V <sub>CC</sub> = MAX			-100		-225	mA	
I <sub>CC</sub>	Supply current (total)	74F125	I <sub>CCH</sub>	V <sub>CC</sub> = MAX	OE <sub>n</sub> = GND, D <sub>n</sub> = 4.5V	17	24	mA	
					OE <sub>n</sub> = D <sub>n</sub> = GND		28	40	mA
					OE <sub>n</sub> = D <sub>n</sub> = 4.5V		25	35	mA
		74F126	I <sub>CCH</sub>	V <sub>CC</sub> = MAX	OE <sub>n</sub> = D <sub>n</sub> = 4.5V		20	30	mA
					OE <sub>n</sub> = 4.5V, D <sub>n</sub> = GND		32	48	mA
					OE <sub>n</sub> = GND, D <sub>n</sub> = 4.5V		26	39	mA
			I <sub>CCL</sub>						
			I <sub>CCZ</sub>						

## NOTES:

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at V<sub>CC</sub> = 5V, T<sub>amb</sub> = 25°C.
- Not more than one output should be shorted at a time. For testing I<sub>OS</sub>, the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I<sub>OS</sub> tests should be performed last.



# Quad buffers (3-State)

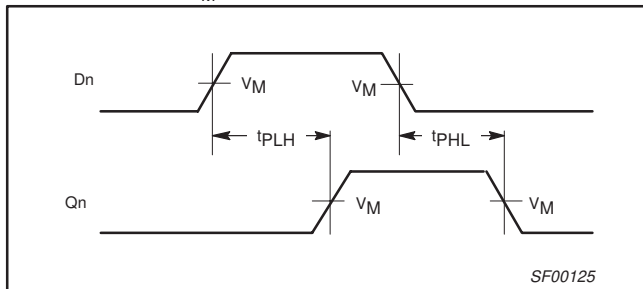
# 74F125, 74F126

## AC ELECTRICAL CHARACTERISTICS

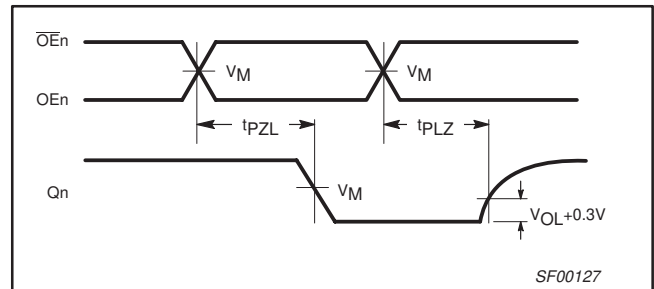
SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$V_{CC} = +5.0V$ $T_{amb} = +25^{\circ}C$ $C_L = 50pF, R_L = 500\Omega$			$V_{CC} = +5.0V \pm 10\%$ $T_{amb} = 0^{\circ}C \text{ to } +70^{\circ}C$ $C_L = 50pF, R_L = 500\Omega$		
			MIN	TYP	MAX	MIN	MAX	
$t_{PLH}$ $t_{PHL}$	Propagation delay Dn to Qn	Waveform 1	2.0	4.0	6.0	2.0	6.5	ns
$t_{PZH}$ $t_{PZL}$	Output Enable time to High or Low level		3.5	5.5	7.5	3.5	8.5	
			4.0	6.0	8.0	4.0	9.0	
$t_{PHZ}$ $t_{PLZ}$	Output Disable time from High or Low level	1.5	3.5	5.0	1.5	6.0		
		1.5	3.5	5.5	1.5	6.0		
$t_{PLH}$ $t_{PHL}$	Propagation delay Dn to Qn	Waveform 1	2.0	4.0	6.5	2.0	7.0	ns
$t_{PZH}$ $t_{PZL}$	Output Enable time to High or Low level		4.0	6.0	7.5	3.5	8.5	
			4.0	6.0	8.0	3.5	8.5	
$t_{PHZ}$ $t_{PLZ}$	Output Disable time from High or Low level	2.0	4.5	6.5	2.0	7.5		
		3.0	5.5	7.5	3.0	8.0		

## AC WAVEFORMS

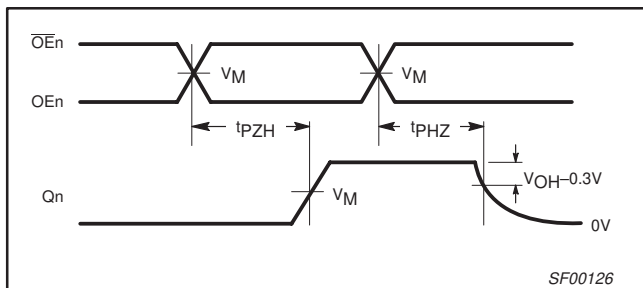
For all waveforms,  $V_M = 1.5V$ .



Waveform 1. Propagation Delay for Input to Output



Waveform 3. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level



Waveform 2. 3-State Output Enable Time to High Level and Output Disable Time from High Level

# Quad buffers (3-State)

# 74F125, 74F126

## TEST CIRCUIT AND WAVEFORM

**Test Circuit for Open Collector Outputs**

**SWITCH POSITION**

TEST	SWITCH
$t_{PLZ}$	closed
$t_{PZL}$	closed
All other	open

**DEFINITIONS:**  
 $R_L$  = Load resistor; see AC electrical characteristics for value.  
 $C_L$  = Load capacitance includes jig and probe capacitance; see AC electrical characteristics for value.  
 $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.

**Input Pulse Definition**

INPUT PULSE REQUIREMENTS						
family	amplitude	$V_M$	rep. rate	$t_w$	$t_{TLH}$	$t_{THL}$
74F	3.0V	1.5V	1MHz	500ns	2.5ns	2.5ns

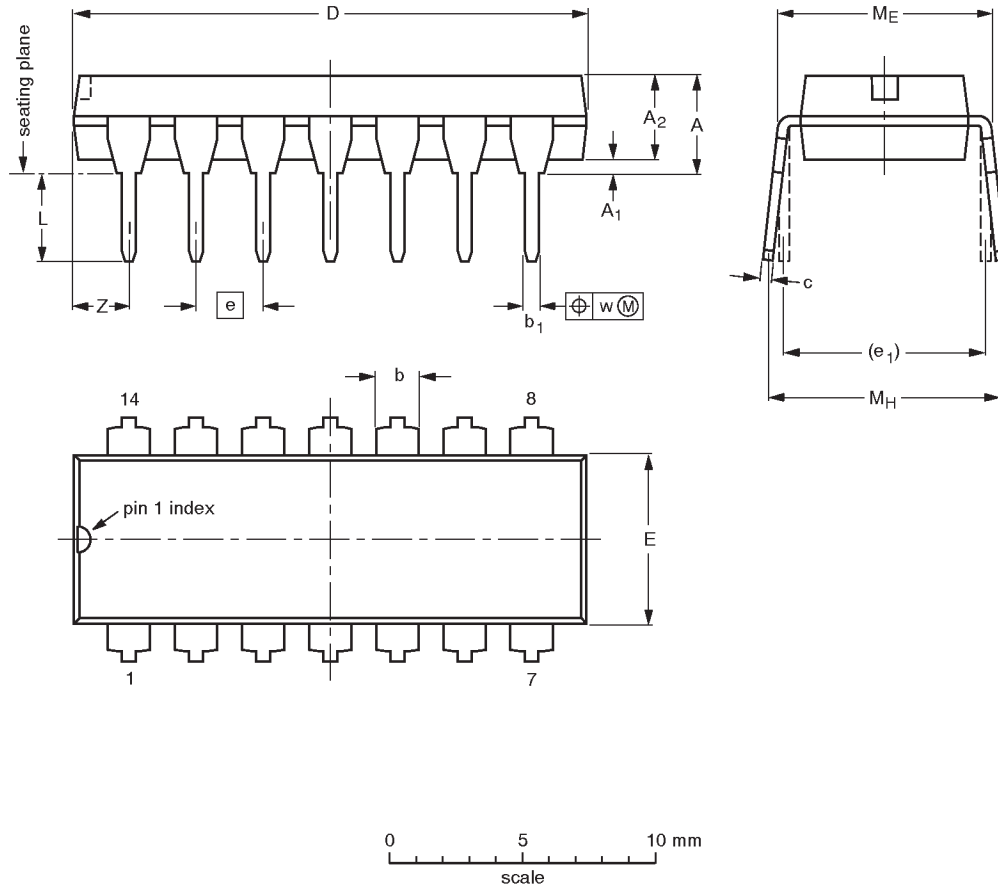
SF00128

# Quad buffers (3-State)

74F125, 74F126

DIP14: plastic dual in-line package; 14 leads (300 mil)

SOT27-1



**DIMENSIONS (inch dimensions are derived from the original mm dimensions)**

UNIT	A max.	A <sub>1</sub> min.	A <sub>2</sub> max.	b	b <sub>1</sub>	c	D <sup>(1)</sup>	E <sup>(1)</sup>	e	e <sub>1</sub>	L	M <sub>E</sub>	M <sub>H</sub>	w	Z <sup>(1)</sup> max.
mm	4.2	0.51	3.2	1.73 1.13	0.53 0.38	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	2.2
inches	0.17	0.020	0.13	0.068 0.044	0.021 0.015	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.087

**Note**

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ		
SOT27-1	050G04	MO-001AA			92-11-17 95-03-11

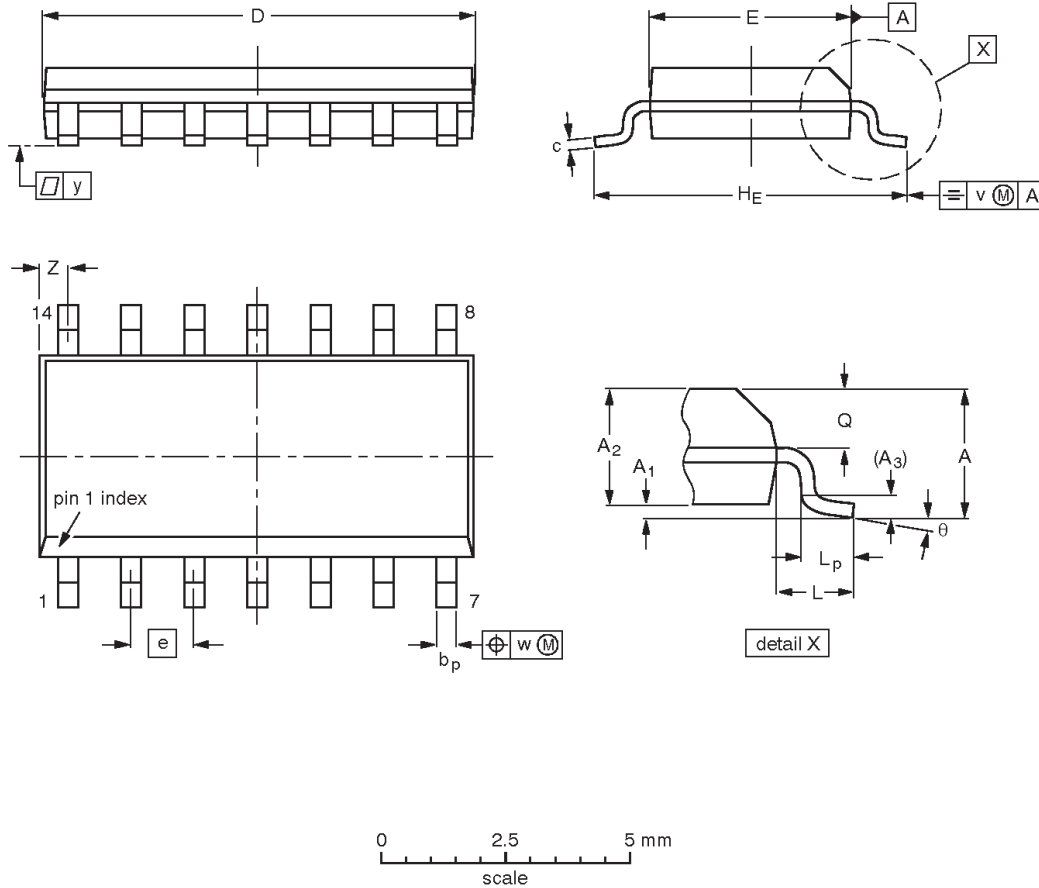


# Quad buffers (3-State)

# 74F125, 74F126

**SO14: plastic small outline package; 14 leads; body width 3.9 mm**

**SOT108-1**



**DIMENSIONS (inch dimensions are derived from the original mm dimensions)**

UNIT	A max.	A <sub>1</sub>	A <sub>2</sub>	A <sub>3</sub>	b <sub>p</sub>	c	D <sup>(1)</sup>	E <sup>(1)</sup>	e	H <sub>E</sub>	L	L <sub>p</sub>	Q	v	w	y	Z <sup>(1)</sup>	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	8.75 8.55	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8° 0°
inches	0.069	0.010 0.004	0.057 0.049	0.01	0.019 0.014	0.0100 0.0075	0.35 0.34	0.16 0.15	0.050	0.244 0.228	0.041	0.039 0.016	0.028 0.024	0.01	0.01	0.004	0.028 0.012	

**Note**

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT108-1	076E06S	MS-012AB				95-01-29 97-05-22

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Quad buffers (3-State)

74F125, 74F126

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**NOTES**

## Quad buffers (3-State)

74F125, 74F126

## Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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print code

Date of release: 10-98

Document order number:

9397-750-05073

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